

BROAD AREA LASER

GaAs Semiconductor Laser Diode
Single Emitter Structure



DATA SHEET

BA Laser

EYP-BAL-0808-06000-2013-SOT12-0001**General Product Information**

Product	Application
808 nm Broad Area Laser	Pulsed Material Processing
sealed SOT Housing for Pulse Mode Operation	Medical

Absolute Maximum Ratings

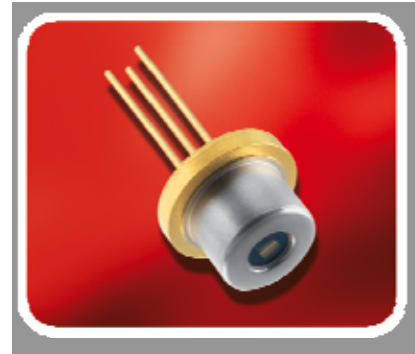
	Symbol	Unit	min	typ	max
Storage Temperature	T_S	°C	-20		85
Operational Temperature at Case	T_C	°C	-20		65
Forward Current	I_F	A			8
Reverse Voltage	V_R	V			0
Peak Output Power	$P_{opt-peak}$	W			8
Forward Voltage	V_F	V			2.7

Recommended Operational Conditions

	Symbol	Unit	min	typ	max
Operational Temperature at Case	T_C	°C	15		40
Forward Current	I_F	A			8
Peak Output Power	$P_{opt-peak}$	W		6.5	

Characteristics at T_{amb} 25 °C at Begin Of Life

Parameter	Symbol	Unit	min	typ	max
Center Wavelength	λ_c	nm	803	808	813
Spectral Width (FWHM)	$\Delta\lambda$	nm		2	
Temperature Coefficient of Wavelength	$d\lambda / dT$	nm / K		0.28	
Slope Efficiency	η_d	W / A	1.0		1.25
Threshold Current	I_{th}	A	0.50	0.85	1.50
Peak Power of first Pulse @ 8A	P_{pulse1}	W	6.5		
Average Electrical Power Consumption	P_{el}	mW			350
Differential Series Resistance	R_S	Ω	0.10	0.15	0.25



Measurement Conditions / Comments

see burst mode characteristics

see burst mode characteristics

see burst mode characteristics

at 6.5 W peak output power

see burst mode characteristics

see burst mode characteristics

Measurement Conditions / Comments

see burst mode characteristics, 8A,
measured pulse 4.000 to 4.150 (integrating)

see burst mode characteristics

during 2 seconds (one burst)

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Parameter	Symbol	Unit	min	typ	max
Cavity Length	L	μm		2000	
Stripe width	Ws	μm		130	
Divergence parallel FWHM	$\Theta_{ }$	$^{\circ}$	7	10	13
Divergence perpendicular (FWHM)	Θ_{\perp}	$^{\circ}$	25	30	35
Polarization				TM	
Spectral Mode (longitudinal)				Multi Mode	

Measurement Conditions / Comments

polarization in perpendicular plane

Burst Mode Characteristics

Parameter	Symbol	Unit	min	typ	max
Pulse Length		μs		5	
Period Length		μs		10	
Duty Cycle		%		50	
Burst Length		ms		200	
Burst Repetition Rate		s^{-1}			0.5

Measurement Conditions / Comments

20.000 pulses

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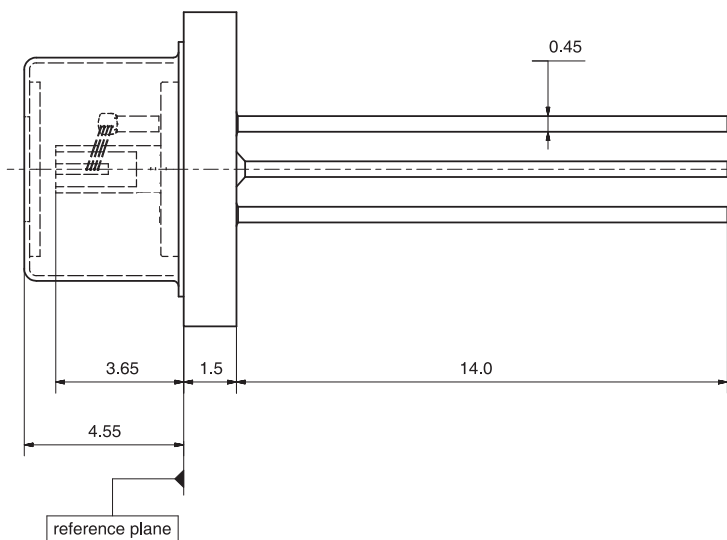
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**DATA SHEET****EYP-BAL-0808-06000-2013-SOT12-0001****Package Dimensions**

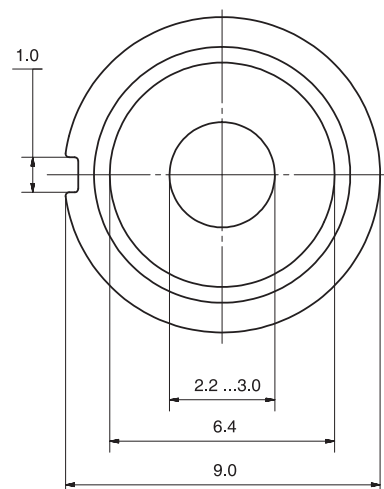
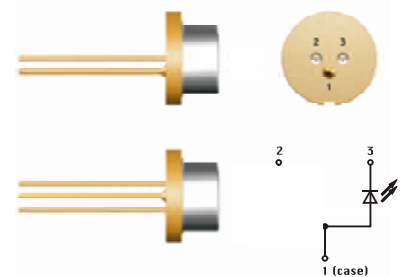
	Symbol	Unit	min	typ	max
Height of Emission Plane	d_{EP}	mm	3.50	3.65	3.70
Excentricity of Emission Center	R	mm			0.12
Pin Length	l	mm		14	

Package Pinout

Laser Anode (+) connected to case	1
not connected	2
Laser Cathode (-)	3

Package Drawings**BA Laser**

reference plane: top side of TO header
reference: center of outer diameter of header



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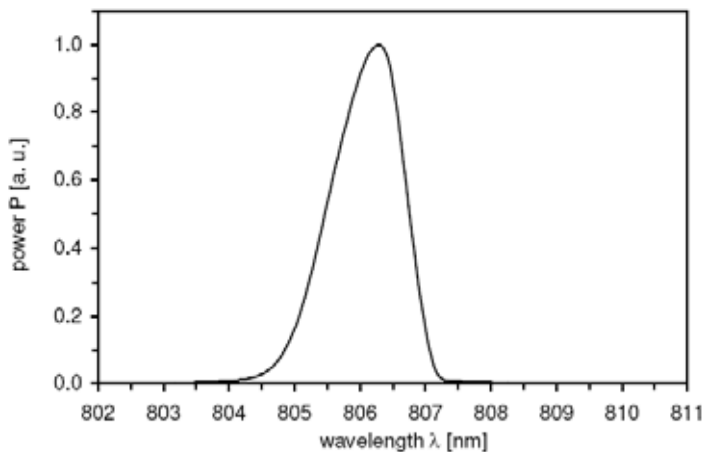


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EYP-BAL-0808-06000-2013-SOT12-0001**Typical Measurement Results**

Spectrum Example at Specified Optical Output Power



Performance figures, data and any illustrative material provided in this specification are typical and must be specifically confirmed in writing by eagleyard Photonics before they become applicable to any particular order or contract. In accordance with the eagleyard Photonics policy of continuous improvement specifications may change without notice.

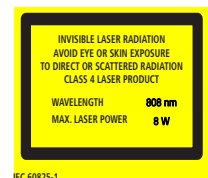
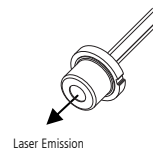
Unpackaging, Installation and Laser Safety

Unpacking the laser diodes should only be done at electrostatic safe workstations (EPA). Though protection against electrostatic discharge (ESD) is implemented in the laser package, charges may occur at surfaces. Please store this product in its original package at a dry, clean place until final use. During device installation, ESD protection has to be maintained.

The BAL diode type is known to be sensitive against thermal stress. Operating at moderate temperatures on proper heat sinks will contribute to a long lifetime of the diode.

The laser emission from this diode is close to the invisible infrared region of the electromagnetic spectrum. Avoid direct and/or indirect exposure to the free running beam. Collimating the free running beam with optics as common in optical instruments will increase threat to the human eye.

Each laser diode will come with an individual test protocol verifying the parameters given in this document.



Complies with 21 CFR 1040.10 and 1040.40

